



BUCKET NO.: 0039-7669-2S

4-18-03

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

RE APPLICATION OF

EIJI SAWA ET AL. : EXAMINER: PATEL, S.

SERIAL NO: 09/538,398 :

FILED: MARCH 29, 2000 : GROUP ART UNIT: 2621

FOR: METHOD AND APPARATUS FOR
INSPECTING PATTERNS :

RECEIVED

APR 18 2003

Technology Center 2600

AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

In response to the Office Action of January 15, 2003, please amend the above-identified application as follows:

IN THE SPECIFICATION

Please amend the specification as indicated below.¹

Please insert ✓ the following heading at page 1, between lines 9 and 10:

FIELD OF THE INVENTION

Please insert ✓ the following heading at page 1, between lines 26 and 27:

DISCUSSION OF THE BACKGROUND

Please replace the paragraph at page 2, lines 12-17, as follows:

¹ A marked-up copy of the amendments is attached hereto.